

Effect of tilt on zone plate performance

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Hard x-ray

Focusing X-Rays

- ▶ Ref. index \rightarrow complex, slightly < 1
- ▶ Zone plates \rightarrow monochromatic diffractive optics.
- ▶ Alternate rings of low/high ref. index materials placed such that outgoing waves interfere constructively.

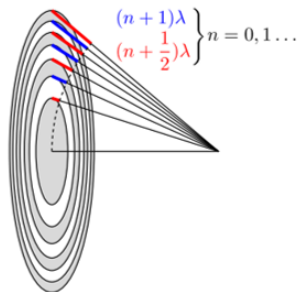
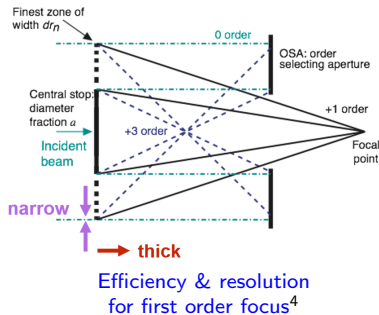


Illustration of zone plate¹

¹ Jacobsen [2019]

Factors affecting efficiency & resolution

- ▶ Spatial resolution limited to finest, outermost zone width.²
- ▶ Zones must be thick enough along beam direction to produce a phase shift of π , several μm at hard x-ray energy.³



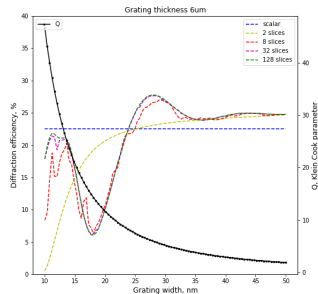
²Baez [1952]; Myers Jr. [1951]

³Kirz [1974]

⁴Jacobsen [2019]

Scalar theory is not enough

- ▶ Scalar approximation assumption → interaction between x-rays and the optic can be treated as one-step diffraction.
- ▶ Klein-Cook param. : Q_{K-C} indicator of "diffraction regime"⁵.



Volume effects in 1d gratings

⁵Klein und Cook [1967]

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Need for tilt misalignment study ⁸

- ▶ As aspect ratios of zone plates go up⁶, degradation of performance due to tilt misalignment becomes more prominent.
- ▶ Analytic limits⁷ from literature do not account for volume diffraction effects.

⁶Chang und Sakdinawat [2014]; Li et al. [2017a]; Parfeniukas et al. [2017]

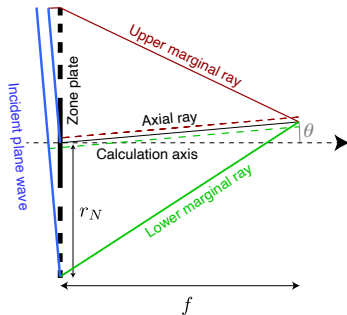
⁷Myers Jr. [1951]; Young [1972]

⁸Tilting zones to local bragg angle is not considered here.

Analytic limits

Analytic limits

- ▶ Based on path length deviation (from no tilt) between marginal, axial ray⁹ → ℓ'_u, ℓ'_l .
- ▶ Simplified expressions for path length deviation
 - ▶ $\ell_u = (\ell_0) + \ell_c \theta - \ell_a \theta^2$
 - ▶ $\ell_l = (\ell_0) + \ell_c \theta + \ell_a \theta^2$
- ▶ $\ell_0 \rightarrow$ convergence to focus, $\ell_c \rightarrow$ coma, $\ell_a \rightarrow$ astigmatism & field curvature¹⁰.



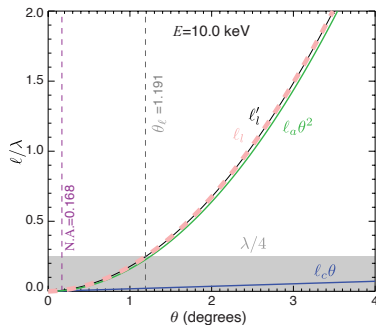
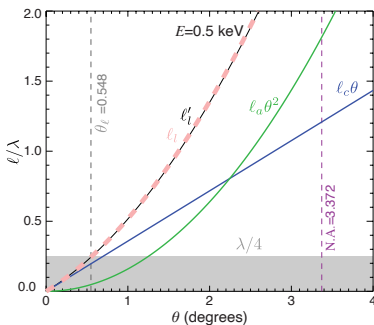
Path length schematic.

⁹Myers Jr. [1951]; Young [1972]

¹⁰referred to hereafter as astigmatism only.

Expected behavior

- ▶ $\frac{\ell_a \theta^2}{\ell_c \theta} \propto \frac{\theta}{N.A.}$
- ▶ RQW limit¹¹: $\theta_c < \frac{1}{2N N.A.} \mid \theta_a < \frac{1}{\sqrt{3}N}$



Path length terms

¹¹Rayleigh Quarter Wave Criterion

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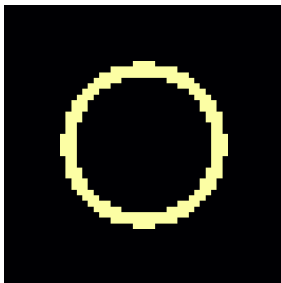
Soft x-ray

Hard x-ray

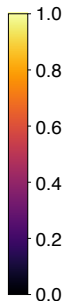
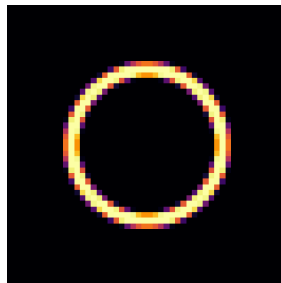
Partial Filling

- ▶ Binary fill on a smaller pixel grid, then downsample!

Binary filling



Partial voxel filling



Partial fil

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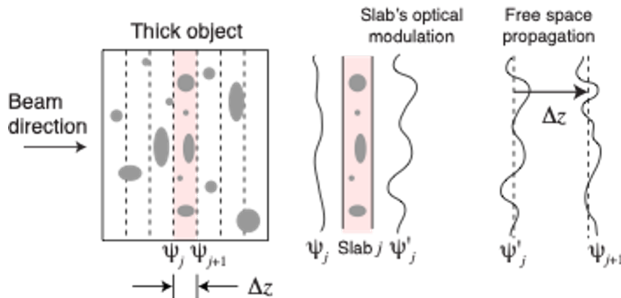
Results

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Hard x-ray

Multislice

- ▶ "Slice" the object into multiple thin sections¹².
- ▶ Agrees with rigorous coupled wave theory¹³.



Multi-slice schematic ¹⁴

¹²Cowley und Moodie [1957], Ishizuka und Uyeda [1977], also known as beam prop. meth. Van Roey et al. [1981]

¹³Li et al. [2017b]

¹⁴Jacobsen [2019]

Algorithm 1: Optic simulation using the multislice method.

```

/* initialize */
 $\psi(x, y) \leftarrow 1$ 
/* diffraction within optic */
for  $n=1, N$  do
    SliceDiff( $n$ )
    PropShort( $\Delta_z$ )
end
/* Propagate exit wave by a focal
length  $f$  to the focal plane */
PropLong( $f$ )

```

Procedure SliceDiff(n)

```

/* Apply refractive effect of slice using */
 $\psi(x, y) = \psi(x, y) \odot \exp\left[i \frac{2\pi\Delta_z}{\lambda} (\delta(x, y) + i\beta(x, y))\right];$ 
return;

```

Procedure PropShort(Δ_z)

```

/* Free space propagation from source  $s$  to
destination  $d$  plane */
 $\psi_s(x, y) \xrightarrow{\mathcal{F}} \Psi(u, v);$ 
 $\Psi(u, v) = \Psi(u, v) \odot \exp\left[-i \frac{2\pi\Delta_z}{\lambda} \sqrt{1 - \lambda^2(u^2 + v^2)}\right];$ 
 $\Psi(u, v) \xrightarrow{\mathcal{F}^{-1}} \psi_d(x, y);$ 
return;

```

Procedure PropLong(f)

```

/* Free space propagation from source  $s$  to
destination  $d$  plane */
 $\psi'(x, y) = \psi_s(x, y) \odot \exp\left[-i \frac{2\pi f}{\lambda} \sqrt{x_s^2 + y_s^2 + f^2}\right];$ 
 $\psi'(x, y) \xrightarrow{\mathcal{F}} \Psi'(x, y);$ 
 $\Psi_d(x, y) = \Psi'(x, y) \odot \exp\left[-i \frac{2\pi f}{\lambda} \sqrt{x_d^2 + y_d^2 + f^2}\right];$ 
 $\psi_d(x, y) = \frac{i\Delta_z^2}{\lambda f} \Psi_d(x, y);$ 
return;

```

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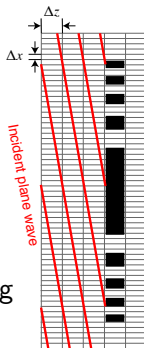
Results

Soft x-ray

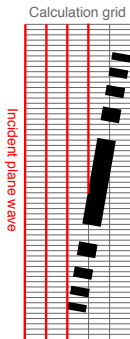
Hard x-ray

Approaches to simulating tilt misalignment

- ▶ Two methods to simulating tilt.
 - ▶ Optic aligned.
 - ▶ Wavefiled aligned.
- ▶ Optic aligned → simple, but limited to cases where output grid can capture focus.
- ▶ Wavefiled aligned → time consuming but no limit on tilt angle.



A: optic-aligned



B: wavefield-aligned

Tilt schematic

Optic aligned approach

- Apply a phase of $\frac{2\pi}{\lambda} x \tan(\theta)$ at each pixel.

Algorithm 2: Optic-aligned approach.

```

/* For each angle in range of interest */
for i=1,K do
    /* initialize */
    AddPhase( $\theta$ )
    /* diffraction within optic */
    for n=1,N do
        SliceDiff(n)
        PropShort( $\Delta_z$ )
    end
    /* Propagate exit wave by a focal length f to the focal plane */
    PropLong(f)
end
Procedure AddPhase( $\theta$ )
    /* Apply phase to mimic tilt misalignment */
     $\psi(x, y) \leftarrow 1$ 
     $\varphi_x = \frac{2\pi\Delta_z}{\lambda} \tan(\theta)x$ 
     $\psi(x, y) = \psi(x, y) \odot \exp[i\varphi_x]$ 
    return
  
```

Wavefield aligned approach

- ▶ Reduce the size of 2D grid to essential area.
- ▶ Duplicate slices along propagation direction to create isotropic grid.
- ▶ Rotate zone plate relative to grid.
- ▶ Collapse the grid back along the propagation direction.

Algorithm 3: Wavefield-aligned approach.

```

/* Reduce the pattern down to
   essential area. */
Reduce (pattern)
/* For each angle in range of
   interest */
for  $i=1, K$  do
    Rotate (pattern_reduced)
    /* For each slice in a zone
       plate at a given tilt
       misalignment perform
       multislice simulation */
    for  $n=1, N$  do
        Extract (pattern_reduced)
        SliceDiff( $n$ )
        PropShort( $\Delta z$ )
    end
    PropLong( $f$ )
end

```

Procedure Reduce (*pattern*)

```

/* Extract relevant part of zone plate */
/* choose and save appropriate parameters viz.
   number of slices, step size along propagation
   direction */
pattern  $\rightarrow$  pattern_reduced ;
return;

```

Procedure Rotate (*pattern_reduced*)

```

/* Rotate zone plate pattern */
/* Expand the number of slices along direction of
   propagation to form an isotropic three
   dimensional grid. */
pattern_reduced  $\xrightarrow{\text{Expand}}$  pattern_isometric;
/* Rotate along axis of rotation */
pattern_isometric  $\xrightarrow{\text{Rotation}}$  pattern_isometric;
/* reduce number of slices to number of slices for
   propagation. */
pattern_isometric  $\xrightarrow{\text{Collapse}}$  pattern_reduced;
return;

```

Procedure Extract (*pattern_reduced*)

```

/* Extract zone plate pattern at slice, expand back
   to grid size needed for propagation. */
pattern_reduced  $\rightarrow$  pattern ;
return;

```

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Parameter \ Regime	Soft X ray	Hard X ray
Photon energy	0.5 keV	10 keV
Outermost zone width dr_N	21.09 nm	21.07 nm
Diameter $2r_N$	58.90 μm	58.88 μm
Pixels N_x	55,296	55,296
Input array pixel size Δ_x	4.73 nm	4.73 nm
Output array pixel size Δ'_x	4.73 nm	4.74 nm
Focal length f	0.5 mm	10 mm
Numerical aperture N.A.	3.372°	0.168°
Bragg tilt angle $^{15}\theta_B(r_N)$	1.687°	0.084°
Aberration tilt limit θ_l	0.548°	1.191°
Max tilt θ_f for optic-alig. approach	10.90°	0.75°
Optimum thickness $t_{zp,opt}$	0.098 μm	1.975 μm
t_{zp} for $Q = 0.333$	0.038 μm	0.759 μm
t_{zp} for $Q = 3.333$	0.381 μm	7.594 μm
t_{zp} for $Q = 10$	1.142 μm	22.782 μm

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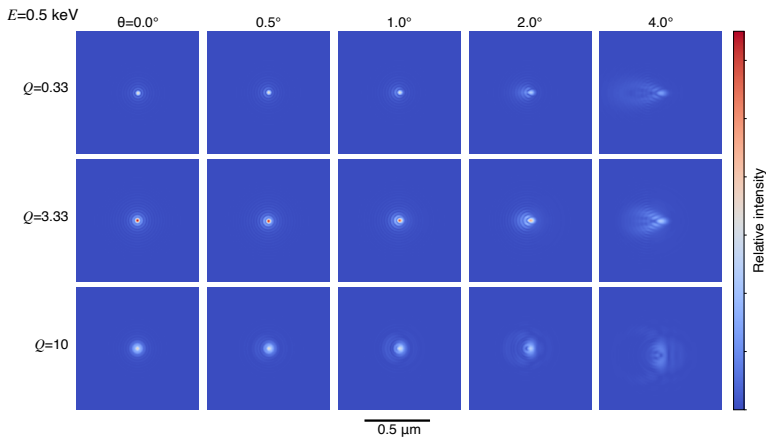
Results

Soft x-ray

Hard x-ray

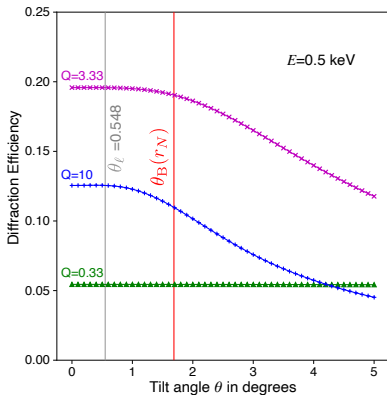
Qualitative performance

- Coma predicted.

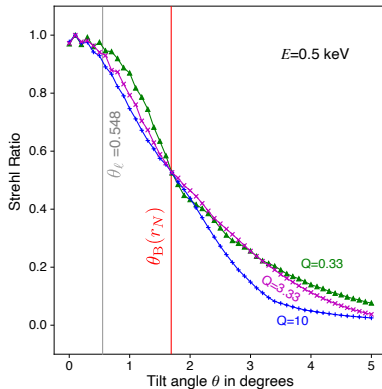


Focal Profile

Quantitative performance



Partial fil



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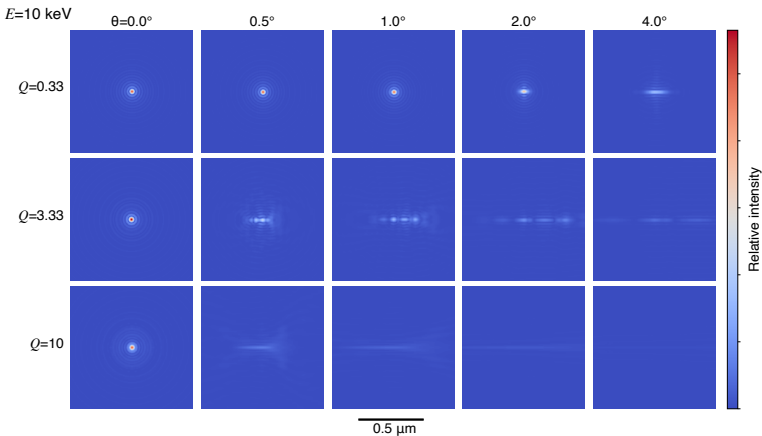
Results

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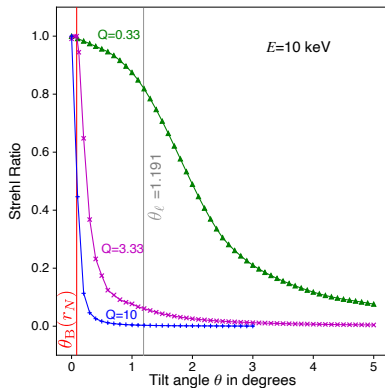
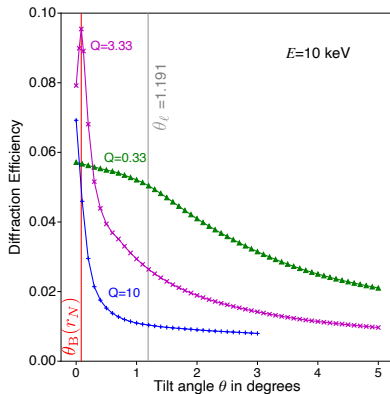
Qualitative performance

- Astigmatism predicted.



Focal Profile

Quantitative performance



Partial fil

Summary

- ▶ Systematic study of tilt misalignment conducted.
- ▶ Simple analytic models can predict misalignment limits and behavior for thin zone plates.
- ▶ Waveguide effects are important for thick zone plates.

Acknowledgements

- ▶ Kenan Li SLAC
- ▶ Michael Wojcik APS,ANL.
- ▶ NIMH U01 MH109100

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